

November 2010 SupreMOS<sup>TM</sup>

# FCP36N60N

# N-Channel MOSFET 600V, 36A, $90m\Omega$

#### **Features**

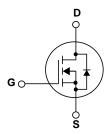
- $R_{DS(on)} = 81 \text{m}\Omega$  ( Typ.)@  $V_{GS} = 10 \text{V}$ ,  $I_D = 18 \text{A}$
- Ultra low gate charge (Typ. Qg = 86nC)
- · Low effective output capacitance
- 100% avalanche tested
- · RoHS compliant

# **Description**

The SupreMOS MOSFET, Fairchild's next generation of high voltage super-junction MOSFETs, employs a deep trench filling process that differentiates it from preceding multi-epi based technologies. By utilizing this advanced technology and precise process control, SupreMOS provides world class Rsp, superior switching performance and ruggedness.

This SupreMOS MOSFET fits the industry's AC-DC SMPS requirements for PFC, server/telecom power, FPD TV power, ATX power, and industrial power applications.





# MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted\*

Symbol	Parameter			FCP36N60N	Units
V <sub>DSS</sub>	Drain to Source Voltage			600	V
V <sub>GSS</sub>	Gate to Source Voltage	Gate to Source Voltage			V
1	Drain Current	-Continuous (T <sub>C</sub> = 25°C)		36	A
I <sub>D</sub>	Drain Current	-Continuous (T <sub>C</sub> = 100°C)		22.7	A
I <sub>DM</sub>	Drain Current	- Pulsed	108	А	
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)			1800	mJ
l <sub>AR</sub>	Avalanche Current			12	А
E <sub>AR</sub>	Repetitive Avalanche Energy			3.12	mJ
dv/dt	MOSFET dv/dt Ruggedness			100	V/ns
uv/ui	Peak Diode Recovery dv/dt		(Note 3)	20	V/ns
n	Dower Dissipation	$(T_C = 25^{\circ}C)$		312	W
$P_{D}$	Power Dissipation	- Derate above 25°C		2.6	W/ºC
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Tempera	ture Range		-55 to +150	°C
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C

<sup>\*</sup>Drain current limited by maximum junction temperature

# **Thermal Characteristics**

Symbol	Parameter	FCP36N60N	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.4	
$R_{\theta CS}$	Thermal Resistance, Case to Heat Sink (Typical)	0.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FCP36N60N	FCP36N60N	TO-220	=	=	50

# **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	eteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 1 \text{mA}, V_{GS} = 0 \text{V}, T_C = 25^{\circ} \text{C}$	600	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 1mA, Referenced to 25°C	-	0.7	-	V/°C
1	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 480V, V <sub>GS</sub> = 0V	-	-	10	
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 480V, V_{GS} = 0V, T_{C} = 125^{\circ}C$ -	-	-	100	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 30V, V_{DS} = 0V$	-	-	±100	nA

# **On Characteristics**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 250 \mu A$	2.0	-	4.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 18A$	-	81	90	mΩ
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 40V, I_{D} = 18A$	-	41	-	S

# **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	1/ /201/ 1/ 01/	-	3595	4785	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 100V, V_{GS} = 0V$ f = 1MHz	-	149	200	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1101112	-	4	6	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 380V, V_{GS} = 0V, f = 1MHz$	-	80	-	pF
C <sub>oss</sub> eff.	Effective Output Capacitance	$V_{DS} = 0V$ to 380V, $V_{GS} = 0V$	-	361	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V		-	86	112	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DS} = 380V, I_{D} = 18A,$	-	15.4	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 10V (Note 4)	-	26.4	-	nC
ESR	Equivalent Series Resistance (G-S)	Drain Open	-	1	-	Ω

# **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		-	23	56	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 380V, I_D = 18A$	-	22	54	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 4.7\Omega$	-	94	198	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)	-	4	18	ns

# **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current		-	-	36	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	108	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 18A	-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 18A	-	574	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	dI <sub>F</sub> /dt = 100A/μs		10	-	μС

- **Notes:**1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2.  $I_{AS}$  = 12A,  $R_G$  = 25 $\Omega$ , Starting  $T_J$  = 25 $^{\circ}$ C
- 3.  $I_{SD} \le 36 \text{A}$ , di/dt  $\le 200 \text{A}/\mu \text{s}$ ,  $V_{DD} = 380 \text{V}$ , Starting  $T_J = 25 ^{\circ} \text{C}$
- 4. Essentially Independent of Operating Temperature Typical Characteristics

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

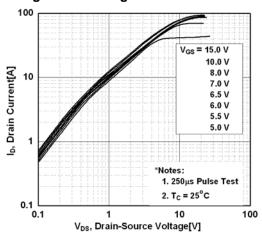
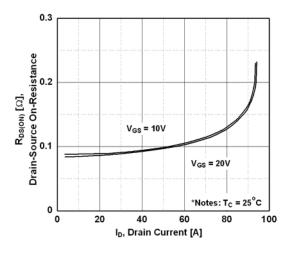


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage



**Figure 5. Capacitance Characteristics** 

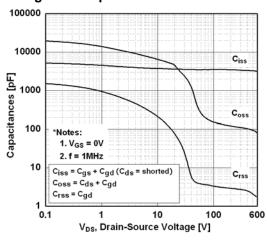


Figure 2. Transfer Characteristics

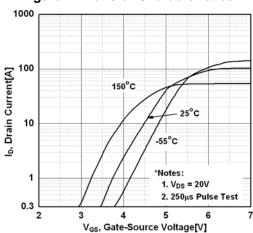


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

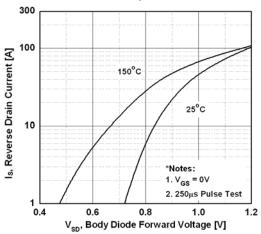
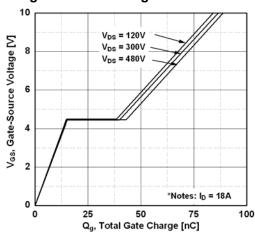


Figure 6. Gate Charge Characteristics



# **Typical Performance Characteristics (Continued)**

Figure 7. Breakdown Voltage Variation vs. Temperature

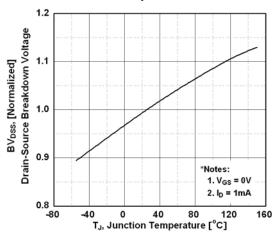


Figure 8. On-Resistance Variation vs. Temperature

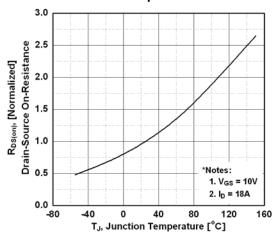


Figure 9. Maximum Safe Operating Area

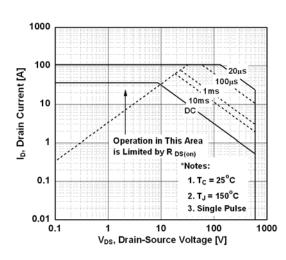


Figure 10. Maximum Drain Current vs. Case Temperature

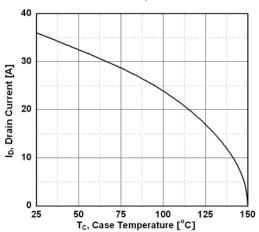
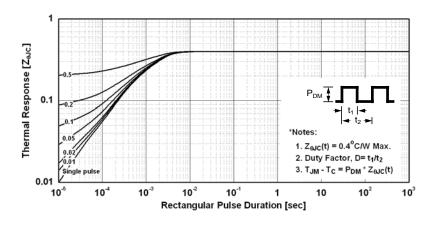
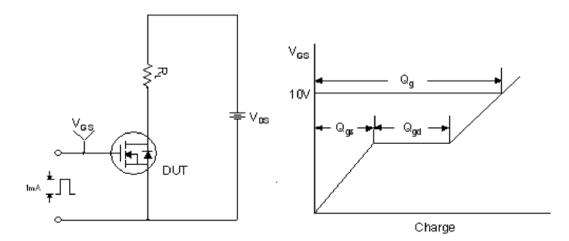


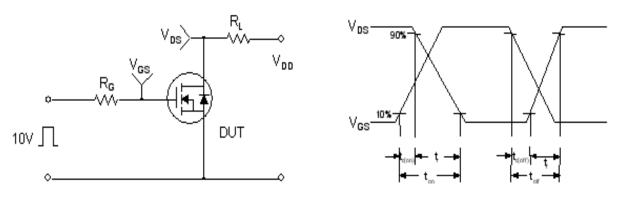
Figure 11. Transient Thermal Response Curve



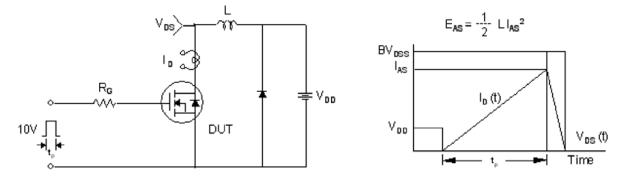
# **Gate Charge Test Circuit & Waveform**



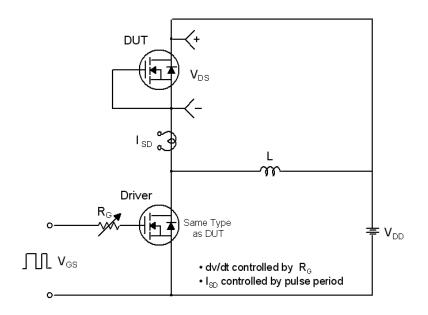
# **Resistive Switching Test Circuit & Waveforms**

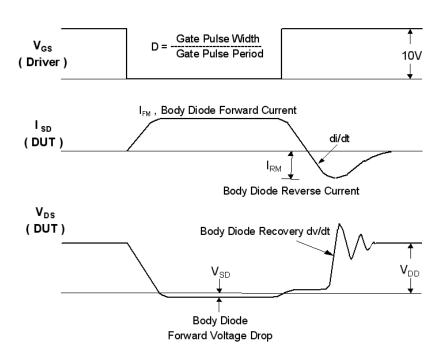


# **Unclamped Inductive Switching Test Circuit & Waveforms**



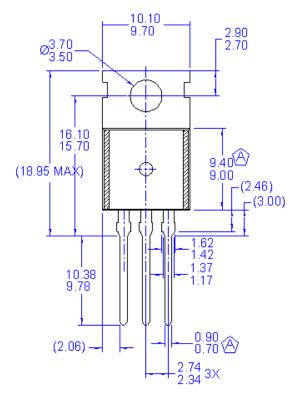
#### Peak Diode Recovery dv/dt Test Circuit & Waveforms

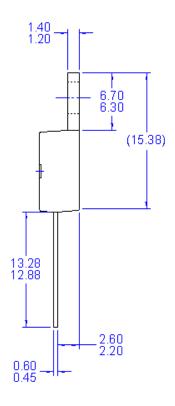


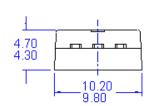


# **Mechanical Dimensions**

# TO-220







#### NOTES:

- (A) CONFORMS TO JEDEC TO-220 VARIATION AB EXCEPT WHERE NOTED
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- D) DRAWING FILE/REVISION: MKT-TO220Y03REV1



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